



US00D567125S

(12) **United States Design Patent**
Okabe et al.

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(54) **STRESS METER**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (8) Cl.** **10-04**

(52) **U.S. Cl.** **D10/81; D10/78; D24/169**

(58) **Field of Classification Search** D10/83, D10/78, 81; D24/224, 232, 169; 205/785.5, 205/787.5, 782; 204/415, 416, 403.2, 403.06, 204/409, 412, 435; 700/17, 431, 499, 866.3; 600/345, 587, 595, 300, 301; 345/824, 156, 345/158; 455/12.1, 86, 406; 422/50-58, 422/61-63, 67, 68.1, 80, 82.03; 435/7.21, 435/14, 22; 340/573.1, 573.3, 573.4

See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a stress meter, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a stress meter; FIG. 2 is a front view thereof; FIG. 3 is a rear view thereof; FIG. 4 is a left side view thereof; FIG. 5 is a right side view thereof; FIG. 6 is a top view thereof; and, FIG. 7 is a bottom view thereof.

1 Claim, 4 Drawing Sheets

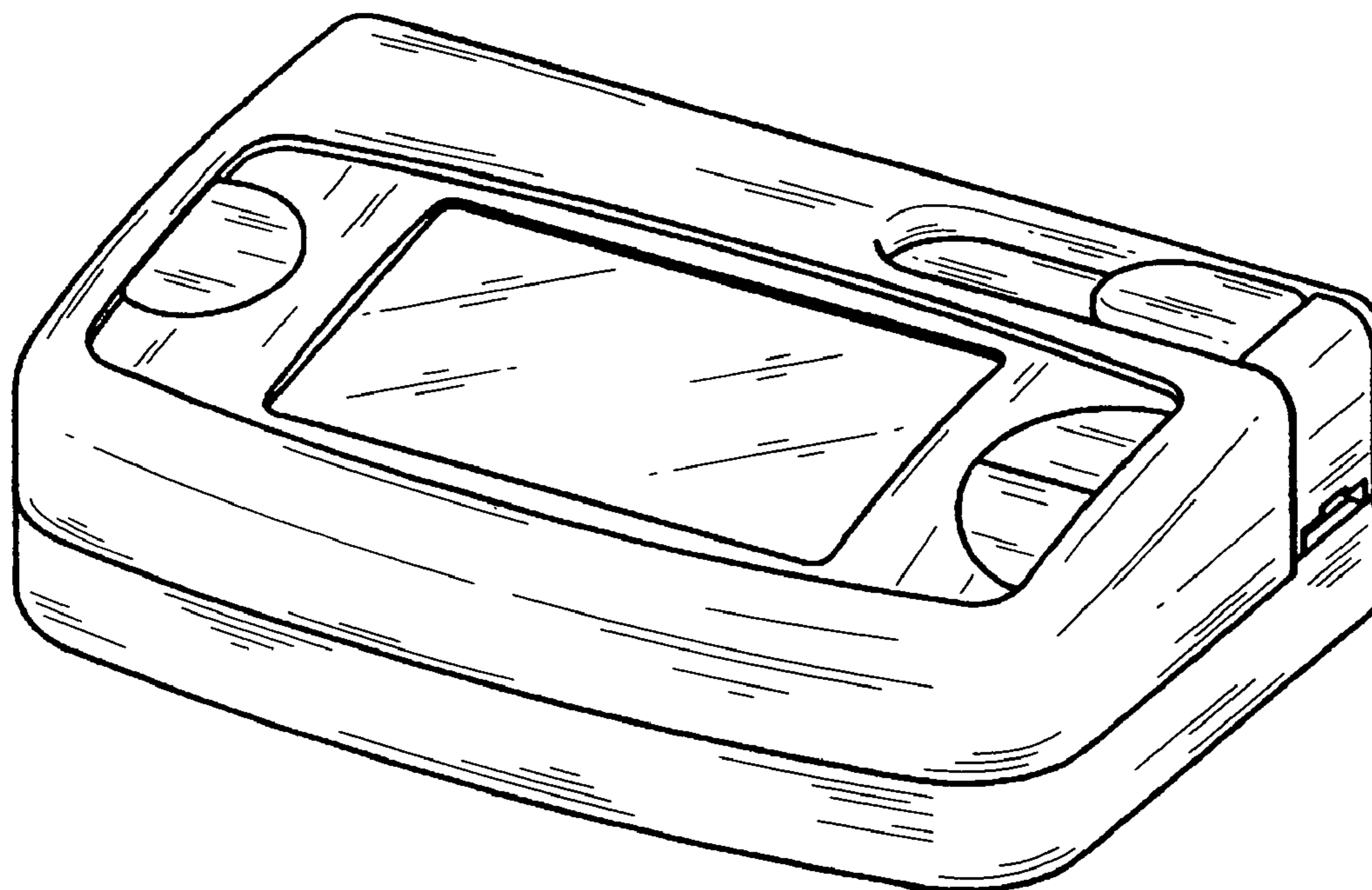


Fig.1

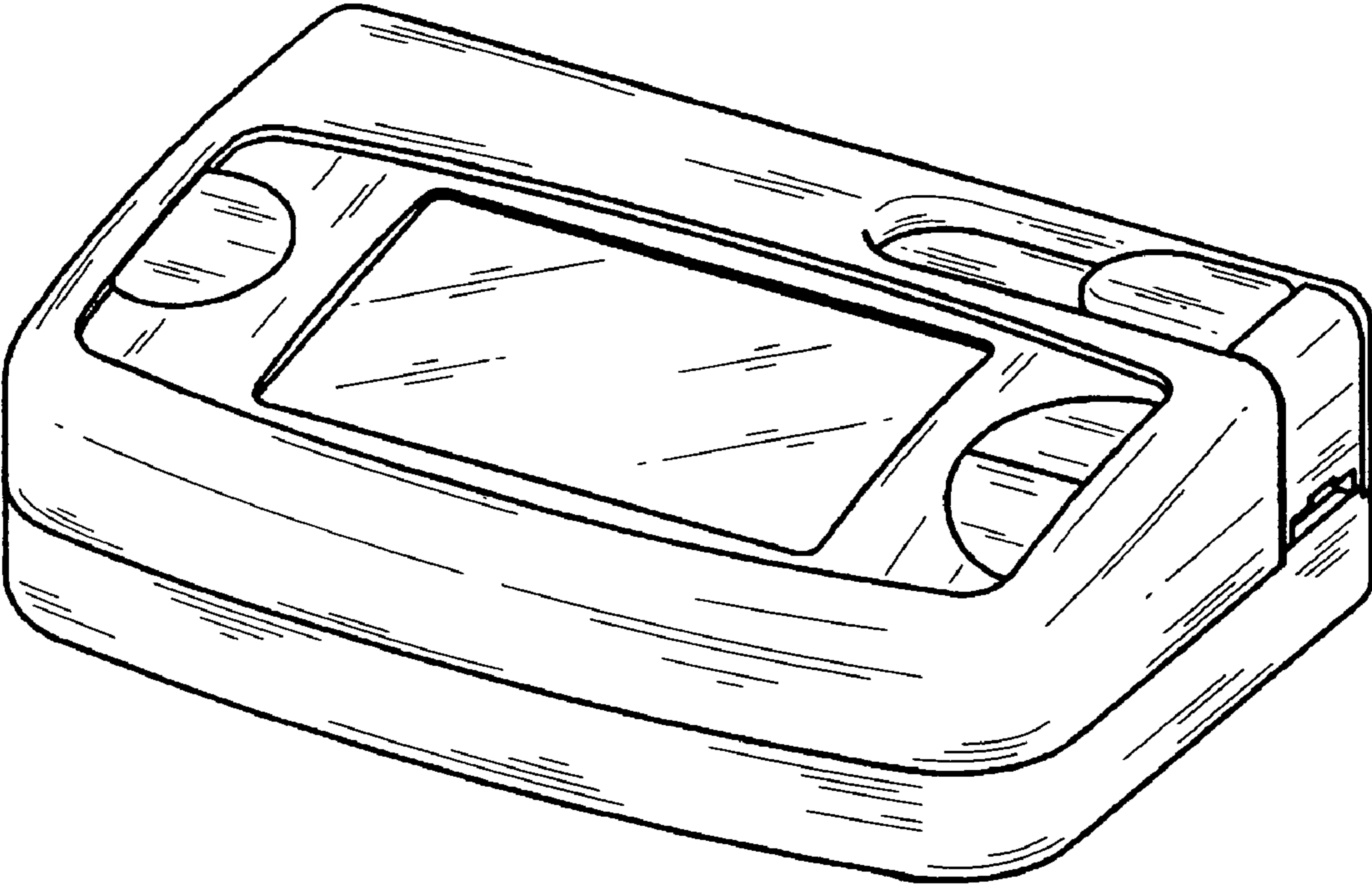


Fig.2

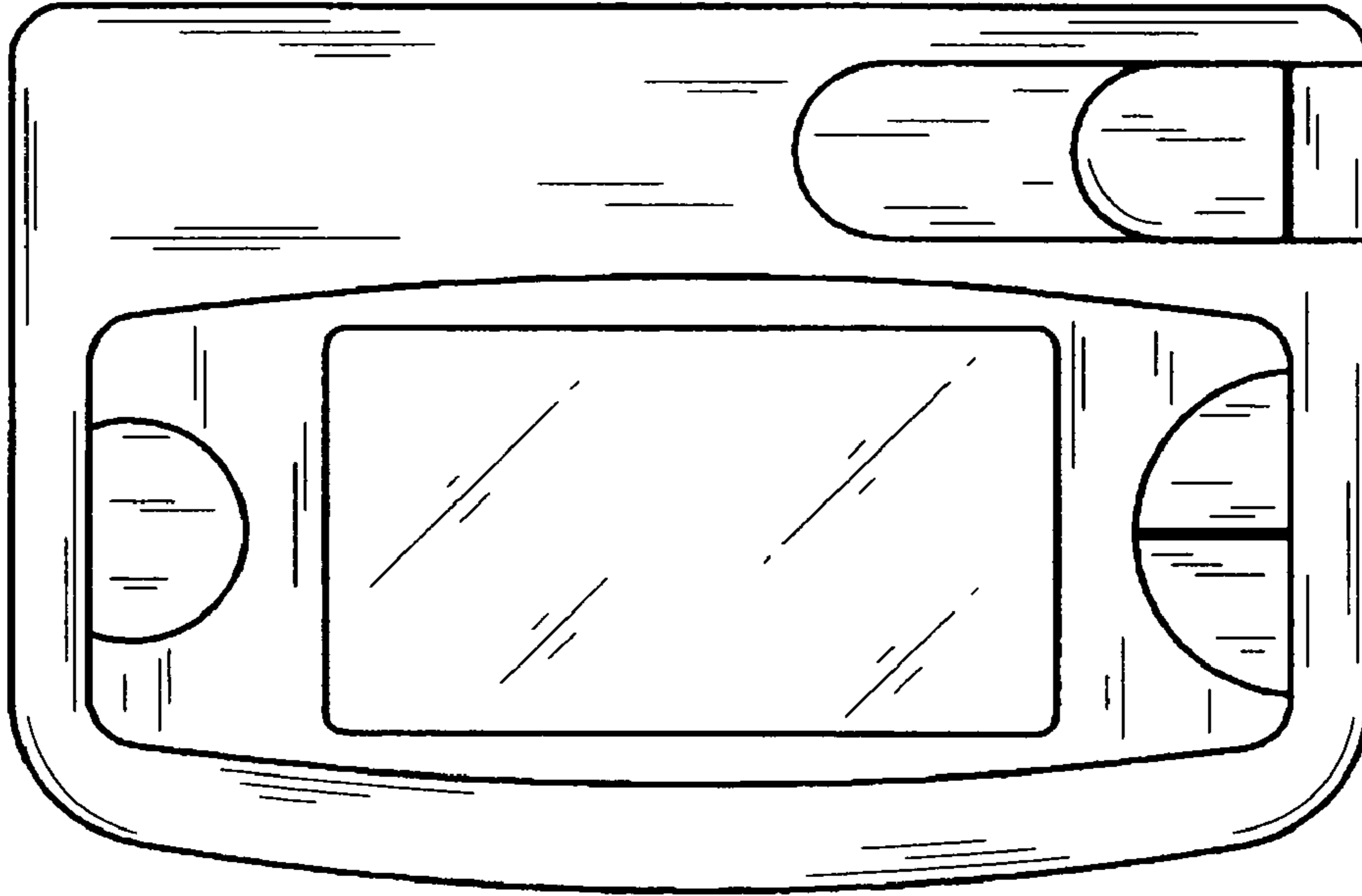


Fig.3

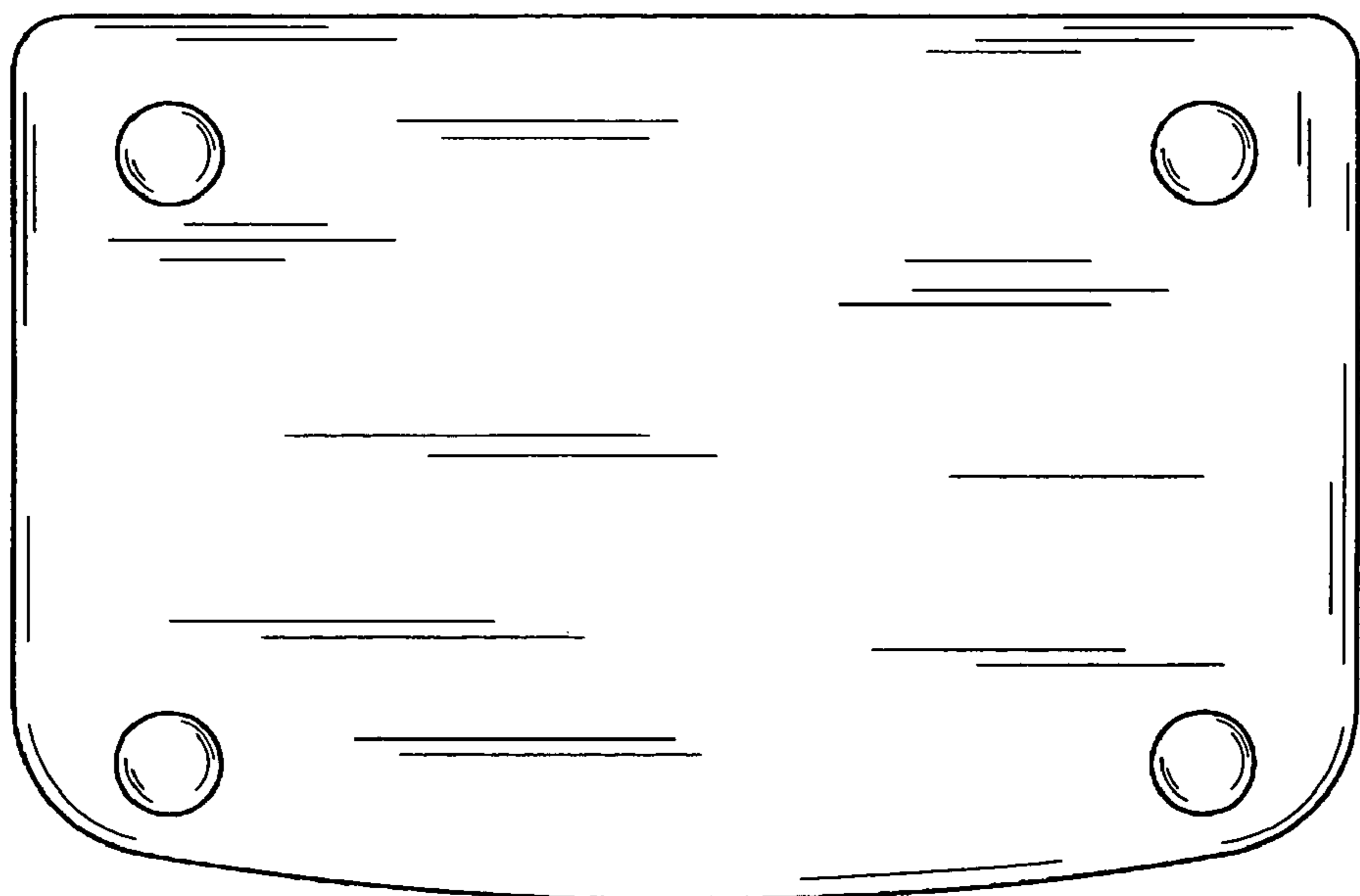


Fig.4

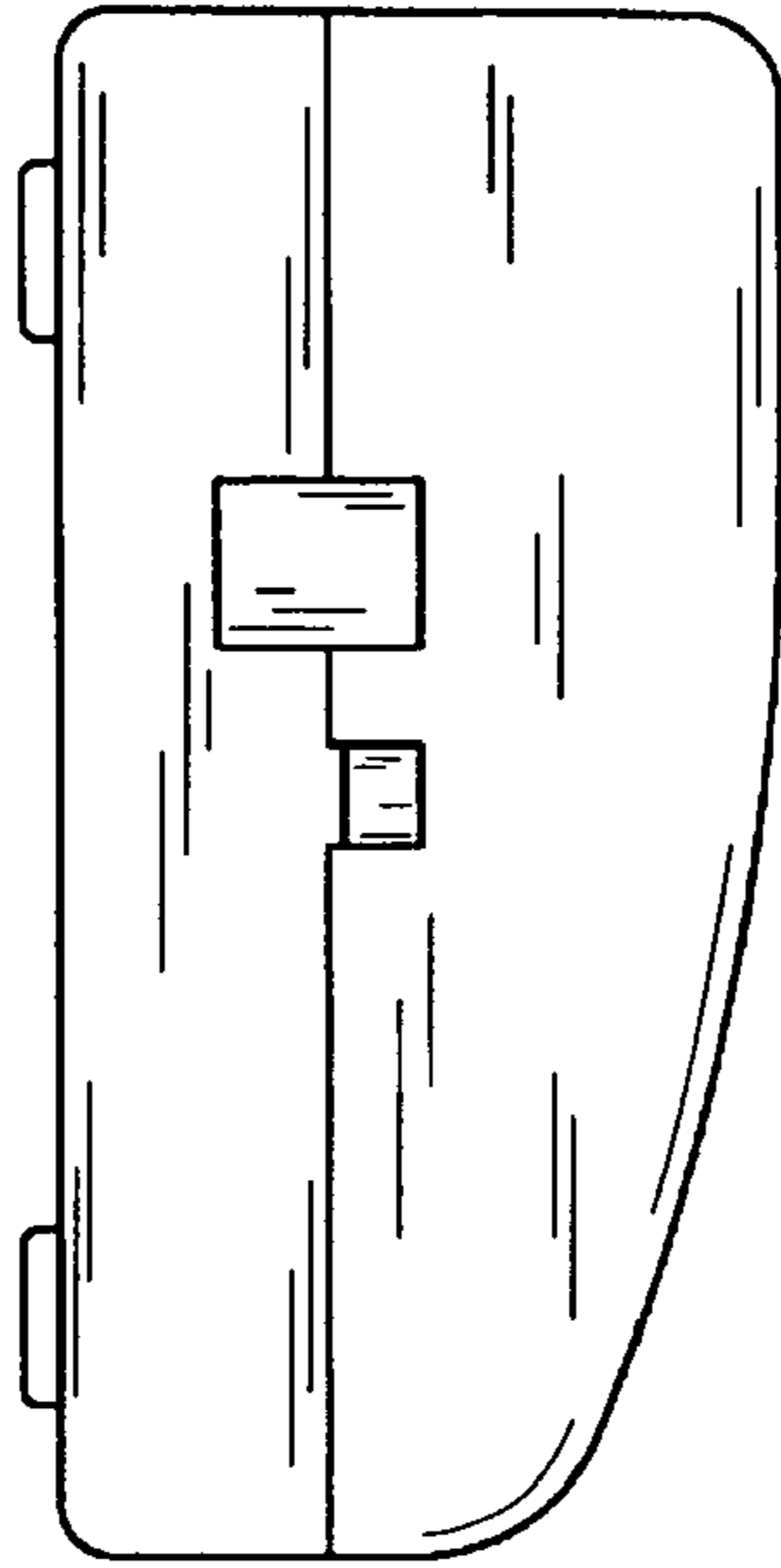


Fig.5

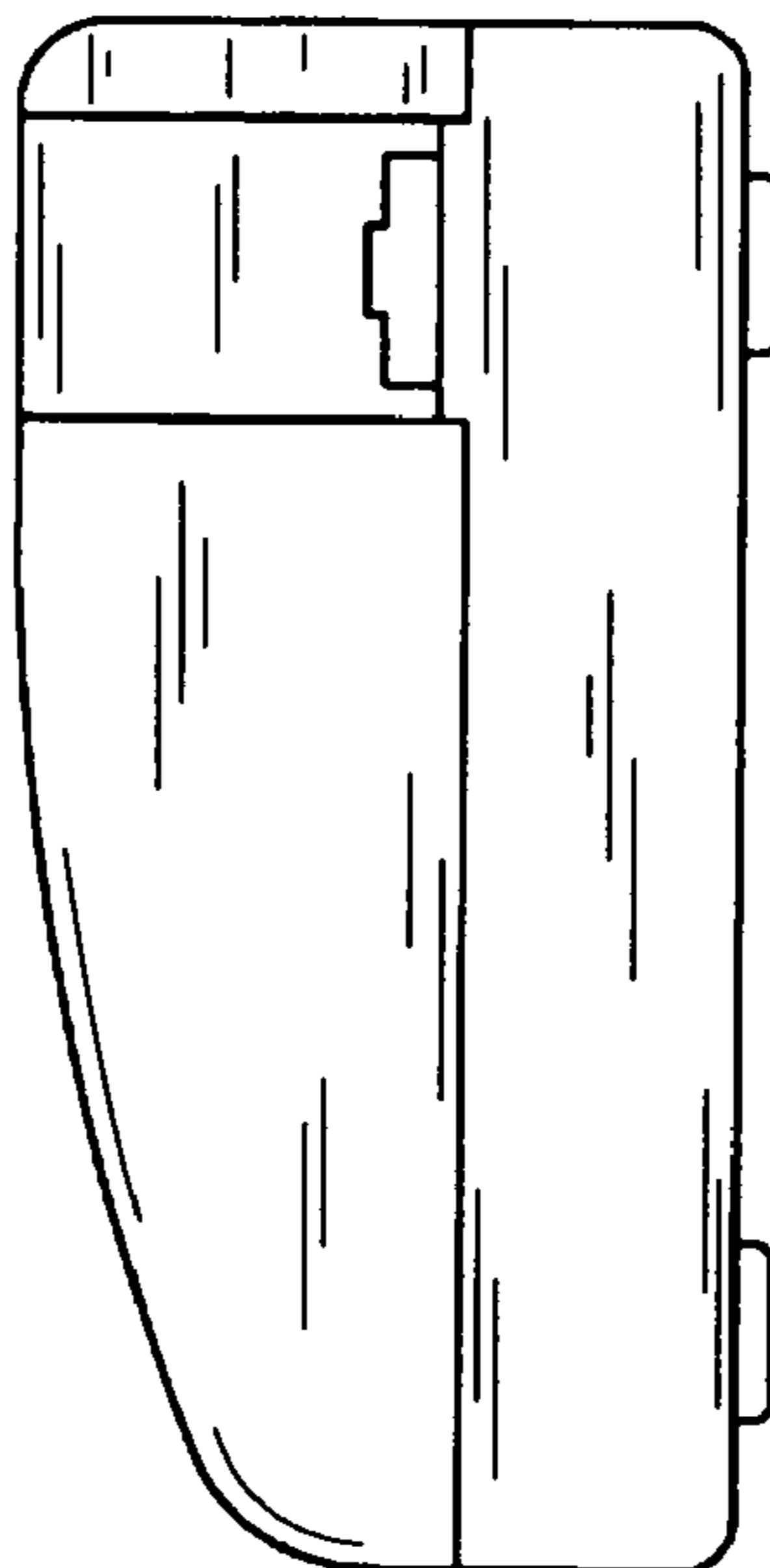


Fig.6

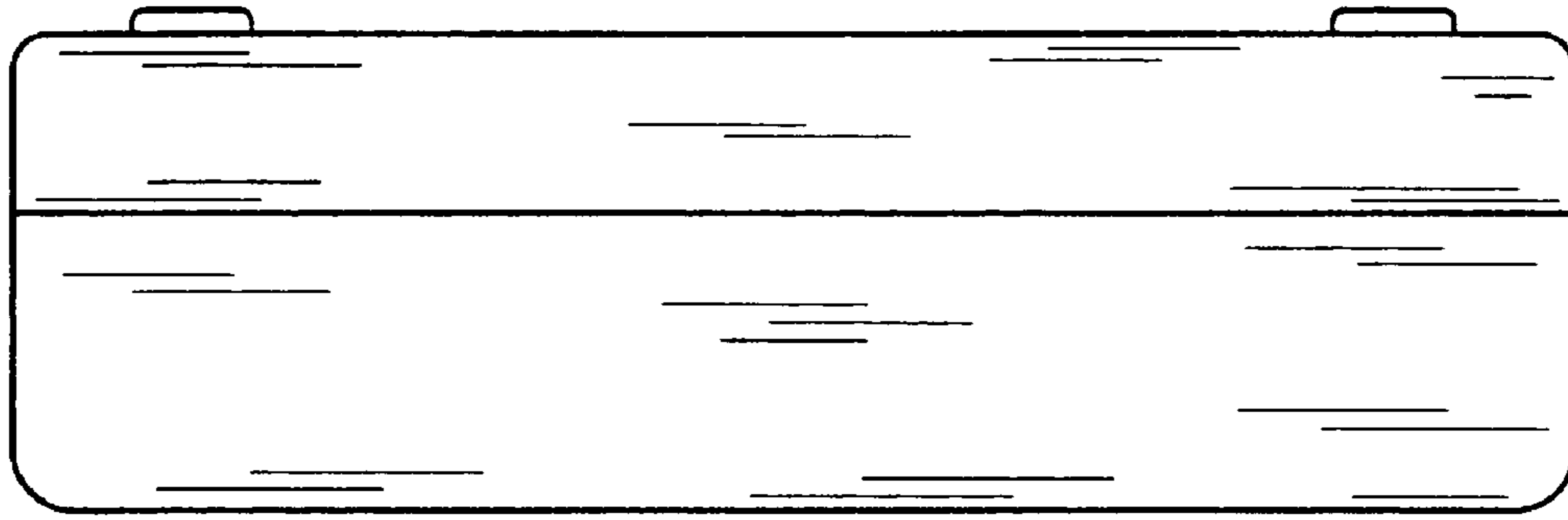


Fig.7

